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**Foreword**

This Standard is one of the series of ECSS Standards intended to be applied together for the management, engineering and product assurance in space projects and applications. ECSS is a cooperative effort of the European Space Agency, national space agencies and European industry associations for the purpose of developing and maintaining common standards. Requirements in this Standard are defined in terms of what shall be accomplished, rather than in terms of how to organize and perform the necessary work. This allows existing organizational structures and methods to be applied where they are effective, and for the structures and methods to evolve as necessary without rewriting the standards.

This Standard has been prepared by the ECSS-Q-60-14C Rev.1 Working Group, reviewed by the ECSS Executive Secretariat and approved by the ECSS Technical Authority.

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Table of contents

[Change log 3](#_Toc525285926)

[1 Scope 6](#_Toc525285927)

[2 Normative references 7](#_Toc525285928)

[3 Terms, definitions and abbreviated terms 8](#_Toc525285929)

[3.1 Terms from other standards 8](#_Toc525285930)

[3.2 Terms specific to the present standard 8](#_Toc525285931)

[3.3 Abbreviated terms 12](#_Toc525285932)

[3.4 Symbols 12](#_Toc525285933)

[4 Environmental parameters for handling and storage for class 1 to 3 programmes 14](#_Toc525285934)

[4.1 General rules and requirements 14](#_Toc525285935)

[4.1.1 Introduction 14](#_Toc525285936)

[4.1.2 Procedures 14](#_Toc525285937)

[4.1.3 Storage area and storage zone 14](#_Toc525285938)

[4.1.4 Cleanliness 14](#_Toc525285939)

[4.1.5 ESD protection 15](#_Toc525285940)

[4.1.6 Packing – Packaging – Handling 15](#_Toc525285941)

[4.1.7 Quality assurance requirements for storage areas 15](#_Toc525285942)

[4.2 Storage conditions 15](#_Toc525285943)

[4.2.1 Air 15](#_Toc525285944)

[4.2.2 Temperature 15](#_Toc525285945)

[4.2.3 Relative humidity (RH) 16](#_Toc525285946)

[4.2.4 Container 16](#_Toc525285947)

[5 Timing parameters for class 1 to 3 programmes 17](#_Toc525285948)

[6 Control parameters for class 1 and class 2 programmes 18](#_Toc525285949)

[6.1 Test requirements 18](#_Toc525285950)

[6.1.1 Requirements per EEE parts family: 18](#_Toc525285951)

[6.1.2 <<deleted>> 22](#_Toc525285952)

[6.1.3 Electrical testing 22](#_Toc525285954)

[6.1.4 External visual inspection 23](#_Toc525285955)

[6.1.5 Seal test 23](#_Toc525285956)

[6.2 Nonconformance 23](#_Toc525285957)

[6.3 Relifing datecode 24](#_Toc525285958)

[6.4 Relifing report 24](#_Toc525285959)

[6.5 Certificate of Conformity 24](#_Toc525285960)

[7 Control parameters for class 3 programmes 25](#_Toc525286303)

[7.1 Test requirements 25](#_Toc525286304)

[7.1.1 Requirements per EEE parts family 25](#_Toc525286305)

[7.1.2 Electrical testing 27](#_Toc525286306)

[7.1.3 External visual inspection 27](#_Toc525286307)

[7.2 Nonconformance 27](#_Toc525286308)

[7.3 Relifing datecode 28](#_Toc525286309)

[7.4 Relifing report 28](#_Toc525286310)

[7.5 Certificate of Conformity 28](#_Toc525286311)

[Annex A <<deleted, recreated as informative Annex C>> 29](#_Toc525286312)

[A.1 <<deleted>> 29](#_Toc525286313)

[A.2 <<deleted>> 29](#_Toc525286319)

[Annex B <<deleted>> 30](#_Toc525286320)

[Annex C (informative) Guidelines for a Relifing report 31](#_Toc525286390)

[C.1 Purpose of the Relifing report 31](#_Toc525286391)

[C.2 Content of the Relifing report 31](#_Toc525286392)

[Bibliography 33](#_Toc525286393)

**Figures**

[Figure 3‑1: Timing parameters 12](#_Toc525286394)

[Figure A-1 : <<deleted>> 29](#_Toc525286489)

[Figure C-1 : Example of a relifing traveller sheet 32](#_Toc525286490)

**Tables**

[Table 5‑1: Timing parameters 17](#_Toc525286491)

[Table 6‑1: Control parameters and detailed application of categories 19](#_Toc525286492)

[Table 6‑1: <<deleted, modified and moved as new Table 6‑1>> 24](#_Toc525286493)

[Table 7‑1: Control parameters and detailed application of categories 26](#_Toc525286494)

# Scope

This standard specifies the requirements, also known as “relifing requirements”, for the planned, intentional storage, control, and removal from storage of electronic, electrical and electromechanical parts which are intended to be used for space applications.

This standard also covers the relifing of commercial components as defined by ECSS-Q-ST-60-13.

The relifing process is a lot quality control activity. The inspections and tests defined do not constitute an up-screening or up-grading of components to a higher level of quality than procured to.

In line with ECSS-Q-ST-60, this standard differentiates between classes of components through different sets of standardization requirements.

The classes provide levels of trade-off between assurance and risk. The highest assurance and lowest risk is provided by class 1 and the lowest assurance and highest risk by class 3. Procurement costs are typically highest for class 1 and lowest for class 3. Mitigation and other engineering measures can decrease the total cost of ownership differences between the three classes. The project objectives, definition and constraints determine which class or classes of components are appropriate to be utilised within the system and subsystems.

1. Class 1 components are described in Clause 4, 5 and 6
2. Class 2 components are described in Clause 4, 5 and 6
3. Class 3 components are described in Clause 4, 5 and 7

The requirements of this document apply to all parties involved at all levels in the integration of EEE components into space segment hardware and launchers.

This standard is not applicable to dice.

This standard may be tailored for the specific characteristic and constrains of a space project in conformance with ECSS-S-ST-00.

# Normative references

The following normative documents contain provisions which, through reference in this text, constitute provisions of this ECSS Standard. For dated references, subsequent amendments to, or revision of any of these publications do not apply, However, parties to agreements based on this ECSS Standard are encouraged to investigate the possibility of applying the more recent editions of the normative documents indicated below. For undated references, the latest edition of the publication referred to applies.

|  |  |
| --- | --- |
| ECSS-S-ST-00-01 | ECSS system – Glossary of terms |
| ECSS-Q-ST-10-09 | Space product assurance – Nonconformance control system |
| ECSS-Q-ST-60 | Space product assurance – Electrical, electronic and electromechanical (EEE) components |
| ECSS-Q-ST-60-13 | Space product assurance – Commercial electrical, electronic and electromechanical (EEE) components |
| ECSS-Q-ST-70-01 | Space product assurance – Cleanliness and contamination control |
| ESCC 24900 | Minimum Requirements for Controlling Environmental Contamination of Components |
| IPC/JEDEC J-STD-033C  February 2012 | Standard for Handling, Packing, Shipping and Use of Moisture/ re-flow Sensitive Surface Mount Devices |
| ESCC 20600 | Preservation, Packaging and dispatch of ESCC Electronic Components |
| ANSI ASQ Z1.4-2003  Revision 2008 | Sampling procedures and tables for inspection by attributes |

# Terms, definitions and abbreviated terms

## Terms from other standards

1. For the purpose of this Standard, the terms and definitions from ECSS-S-ST-00-01 apply, in particular for the following terms:
   1. clean area
   2. cleanliness
   3. cleanroom
   4. component
   5. conformance
   6. contamination
   7. dependability
   8. environment
   9. inspection
   10. performance
   11. relifing
   12. traceability

## Terms specific to the present standard

1. antistatic material

material that minimizes the generation of static charges

1. 1 This term refers to the reduction of triboelectric charge generation.
2. 2 This property is not dependent upon material resistivity.
3. conductive material

<CONTEXT: ESD protection> material with the following characteristics:

* surface conductive type: materials with a surface resistivity less than 105 Ω/🞎.
* volume conductive type: materials with a volume resistivity less than 104 Ω-cm.

1. container

receptacle which holds, restrains or encloses an item for the purpose of storage or transportation

1. (original) date code

code used by the EEE part manufacturer at assembly step that indicates the production date

1. 1 Generally four-figure codes; two for the year and two for the week.
2. 2 Special lot number can also identify the date code.
3. (relifing) date code:

code indicating the date an item is submitted to the last step of the relifing sequence.

1. Four-figure code, two for the year and two for the week.
2. dissipative material

<CONTEXT: ESD protection> material with the following characteristics:

* surface conductive type: materials with a surface resistivity equal to or greater than 105 Ω/🞎 but less than 1012 Ω/🞎.
* volume conductive type: materials with a volume resistivity equal to or greater than 104 Ω-cm but less than 1011 Ω-cm.

1. electrostatic charge

negative or positive electrical charge present on the material or item surface, at rest

1. electrostatic discharge (ESD)

transfer of electrostatic charge between objects at different potentials caused by direct contact or induced by an electrostatic field

1. electrostatic discharge sensitive (ESDS)

tendency of the performance of EEE parts to be affected or damaged by an ESD event

1. ESD protected area

area which is constructed and equipped with the necessary ESD protective materials, equipment, and procedures, to limit ESD voltages below the sensitivity level of ESDS items handled therein

1. ESD protective material

material with one or more of the following properties: limits the generation of electrostatic charge, dissipates electrostatic charge, and provides shielding from electric fields

1. ESD protective packaging

packaging with ESD protective materials to prevent ESD damage to ESDS items

1. electrostatic shield

barrier or enclosure that prevents or attenuates the penetration of an electric field

1. handled or handling

actions during which items are hand manipulated or machine processed

1. identification

application of appropriate markings to ensure that the identity of an item is unfailingly indicated after preservation and each stage of packing

1. isolating material

<CONTEXT: ESD protection> material not defined as conductive or dissipative are considered to be isolating

1. package

support used for enveloping, protecting or containing materials

1. Different types of packages are normally used: Primary, intermediate and final packages
2. (primary) package

container, envelope or wrap holding an individual item

1. (intermediate) package

container holding two or more primary packages

1. (final) package

container holding one or more intermediate packages, used for transportation of supplies to the orderer

1. packaging

operations consisting in the preparation of supplies for transit and delivery.

1. The term includes preservation, identification and packing
2. packing

operation by which supplies are placed in container or wrapped and placed in containers

1. particle

unit of matter with observable length, width and thickness

1. A particle can be object of solid or liquid composition, or both, and generally between 0,001 μm and 1000 μm in size
2. preservation

cleaning of an item and the application of a suitable temporary protective, where necessary, to maintain the item in prime condition

1. relifing procedures

set of tests performed on an item previously stored to verify that its initial quality and reliability have not been affected by time

1. storage area

area in the storage site where EEE parts are stored and which contains one or more storage zones.

1. storage long duration

storage for which duration exceeds 3 years

1. storage site

geographical location where EEE parts are stored for a short, medium or long term period

1. For this site the requirements given in this standard apply: EEE parts manufacturer’s premises, procurement Agency, EEE part user.
2. storage zone

defined space in which EEE parts are stored and which is equipped for the monitoring and the control of storage conditions.

1. timing parameters

One of the following parameters:

* T0 : Original date code
* T1 : Maximum allowed storage period from T0 with no relifing   
   control
* T2 : Maximum duration between the original date code of part and its mounting
* dT : Maximum allowed storage period after a relifing control which can be repeated once.

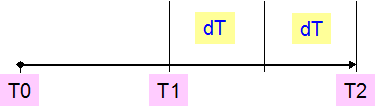


Figure 3‑1: Timing parameters

1. triboelectric effect

generation of electrostatic charge on an object by rubbing or other type of contact.

## Abbreviated terms

For the purpose of this Standard, the abbreviated terms from ECSS-S-ST-00-01 and the following apply:

| Abbreviation | Meaning |
| --- | --- |
| ASIC | application specific integrated circuit |
| CCD | charge coupled device |
| CDM | charge device model |
| DPA | destructive physical analysis |
| DSP | digital signal processor |
| EEE | electronic, electrical and electromechanical |
| ESCC | European space components coordination |
| ESD | electrostatic discharge |
| FPGA | field programmable gate arrays |
| HBM | human body model |
| JEDEC | joint electronic devices engineering council |
| MM | machine model |
| MMIC | microwave monolithic integrated circuit |
| NA | not applicable |
| NCR | nonconformance report |
| NSA | national space agency |
| RH | relative humidity |
| SCSB | space components steering board |
| VLSI | very large scale integration |

## Symbols

|  |  |
| --- | --- |
| **Ω** | ohm |
| **Ω/**🞎 | ohm per square |
| **Ω-cm** | ohm centimetre |
| **μm** | micrometer |
| **V** | volt |

# Environmental parameters for handling and storage for class 1 to 3 programmes

## General rules and requirements

### Introduction

This clause defines the rules for handling and storing EEE parts used on space programs.

Those rules are in line with the requirements defined in ESCC Basic Specification 24900.

### Procedures

The following domains shall be covered and documented by procedures sent to the customer for information, on request:

Storage area and storage zone

Cleanliness

ESD protection

Packing and Packaging

Handling

Quality assurance.

### Storage area and storage zone

It shall be demonstrated that storage areas and storage zones provide such protection against vibration, electromagnetic fields, radiation fields and against light so that possible degradation of organic packaging material is prevented.

### Cleanliness

Rules for cleanliness efficiency shall be implemented.

The working areas and the contained equipment shall be maintained as visually clean with no loose material.

Access rules shall apply for personnel, materials and equipment.

Storage areas shall conform to a cleanliness level as defined in ECSS-Q-ST-70-01 clause 5.3.1.4.

1. This cleanliness level is often called and known as “grey zone”.

### ESD protection

The efficiency of ESD protection measures in storage, handling and testing areas shall be demonstrated.

1. <<deleted>>

### Packing – Packaging – Handling

ESCC 20600 or IPC/JEDEC J-STD-033 shall apply for packing, packaging and handling.

1. <<deleted>>

### Quality assurance requirements for storage areas

The storage responsible entity shall establish and document the following:

Prohibited materials

Personnel access rules

Prohibited personnel actions

Measures and facilities to segregate and protect components during receiving, inspection, storage and delivery

Control measures to ensure that electrostatic discharge susceptible components are identified and handled only by trained personnel using anti static packaging and tools.

## Storage conditions

### Air

Normal air is used.

### Temperature

Temperature in the immediate vicinity of stored components shall at all times be maintained between a minimum temperature of 17 °C and a maximum temperature of 27 °C.

1. This is to avoid chemical reactions catalysis when it is too high or electronic reactions on certain technologies when it is too low.

### Relative humidity (RH)

RH in store cupboards shall be kept in the range 20 % to 65% of RH.

1. This is to avoid, when combined with temperature, corrosion phenomena. The lower is the Relative Humidity the greater is the probability for ESD damage.

Commercial parts encapsulated in plastic package shall be stored, before and after relifing test sequence, in one of the following conditions:

Nitrogen,

Dry and ionised air in a range of 15 % to 25 % RH,

Dry packs as specified in J-STD-033C (February 2012).

### Container

The containers used during storage shall ensure protection against ESD as defined in clause 4.1.6 and against any form of corrosion or contamination.

Parts shall be stored in containers such that it can be demonstrated that they offer protection against ESD, corrosion and contamination including the contamination induced by the package itself.

1. Their primary containers can be used as long as they meet this requirement.

CCDs and opto-electronic sensors shall be stored in dry air or in neutral ambience, to prevent risks of cover glass pollution and moisture ingress.

# Timing parameters for class 1 to 3 programmes

When used, relifing shall be performed anywhere between T1 and T2 according to the timing parameters definition as given in definition 3.2.30.

1. 1 Relife can be anticipated before T1, provided dT remains applicable.
2. 2 For parts not planned to be mounted and to be kept in stock, relifing is not mandatory.

Table 5‑1: Timing parameters

|  |  |  |  |
| --- | --- | --- | --- |
|  | T1 | T2 | dT |
| All components (except savers) | 7 years | 15 years | 4 years |
| Savers | 15 years | NA | NA |

In case of parts procured through an external procurement entity, the customer should require the supplier to state the minimum period of validity of parts, w.r.t. T1 or T2, after delivery.

All relifing tests as described in Table 6‑1 and **Error! Reference source not found.** shall be completed in maximum period of six weeks.

# Control parameters for class 1 and class 2 programmes

## Test requirements

### Requirements per EEE parts family:

For relifing, the following tests, as specified in Table 6‑1 shall be performed:

External Visual Inspection

Electrical measurements

Seal test

Specific test

Component families not covered in Table 6‑1 shall be subject to special procedures to be defined by the program.

1. The relifing procedure can be applied on a sub-lot containing only the quantity of components immediately needed for production. In this case, the relifing date-code is applicable only to parts actually tested. The time limits specified in Table 5‑1 remain applicable for the residual sub-lot.

When sampling is specified in Table 6‑1, it shall be performed in accordance with AQL 0,65 % level II according to ANSI ASQ Z1.4.

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The specifications and methods to be used during relifing shall be those that were in effect for the initial procurement or, if demonstrated that they are not applicable, the most recent updated issues.

Table 6‑1: Control parameters and detailed application of categories

|  | External Visual Inspection | ELECTRICAL (6.1.1o) | SEAL (6.1.1e) | SPECIFIC TESTS |
| --- | --- | --- | --- | --- |
| **capacitors, chip, ceramic** | sampling | sampling  (6.1.1f) | no | no |
| **capacitors, moulded, ceramic** | sampling (6.1.1g) | sampling  (6.1.1f, 6.1.1g) | no | no |
| **capacitors, glass (CYR, …)** | 100 % | 100 % | no | no |
| **capacitors, mica (HTxx, …)** | 100 % | 100 % | no | no |
| **capacitors, chip, solid tantalum**  **(TAJ, T495, CWR11, …)** | sampling | 100 % | no | yes (6.1.1h) |
| **capacitors, leaded, solid tantalum**  **(CSR, …)** | sampling | 100 % | no | yes (6.1.1h) |
| **capacitors, leaded,**  **non solid (tantalum,(CLR79, …)** | 100 % | 100 % | no | yes (6.1.1i) |
| **capacitors, film**  **(CRH, CHS, PMxx, MKTS, …)** | sampling | 100 % | no | yes (6.1.1j) |
| **capacitors, variable** | sampling | no | no | no |
| **connectors, non filtered, rectangular** | 100 % | no | 100 % | no |
| **connectors, filtered, rectangular** | 100 % | 100 % | 100 % | no |
| **connectors, non filtered, circular** | 100 % | no | 100 % | no |
| **connectors, filtered, circular** | 100 % | 100 % | 100 % | no |
| **contacts & accessories** | No | no | no | no |
| **crystals** | 100 % | 100 % | 100 % | no |
| **diodes** | 100 % | sampling | 100 % | no |
| **diodes, microwave** | 100 % | sampling | 100 % | no |
| **filters** | 100 % | 100 % | 100 % | no |
| **fuses, "cermet"** | sampling | sampling | no | no |
| **fuses, wire link** | sampling | sampling | no | no |
| **heaters, flexible** | 100 % | 100 % | no | no |
| **inductors, coils, moulded** | sampling | sampling | no | no |
| **inductors, coils, non moulded** | sampling | sampling | no | no |
| **integrated circuits** | 100 % | sampling  (6.1.1k, 6.1.1l) | 100 % | no |
| **integrated circuits, microwave** | 100 % | sampling  (6.1.1l) | 100 % | no |
| **µwave passive parts (isolators, circulators)** | 100 % | sampling | no | no |
| **µwave passive parts**  **(power dividers, couplers)** | 100 % | sampling | no | no |
| **µwave passive parts (attenuators, loads)** | 100 % | sampling | no | no |
| **oscillators (hybrids)** | 100 % | 100 % | 100 % | no |
| **relays, electromagnetic,**  **latching and non-latching** | 100 % | 100 %  (6.1.1m) | 100 % | no |
| **resistors, fixed, film**  **(RNC, MBx xxxx, ...) (except RNC90)** | sampling | 100 % | no | no |
| **resistors, high precision,**  **fixed, metal foil (RNC90, ...)** | sampling | 100 % | no | no |
| **resistors, network, thick and thin film** | sampling | 100 % | no | no |
| **resistors, current sensing (RLV, ...)** | sampling | 100 % | no | no |
| **resistors, power, fixed, wirewound**  **(RWR, ...)** | sampling | sampling | no | no |
| **resistors, power, fixed, wirewound, chassis mounted (RER, ...)** | sampling | sampling | no | no |
| **resistors, precision, fixed,**  **wirewound (RBR, ...)** | sampling | 100 % | no | no |
| **resistors, fixed, film, high voltage**  **(RHV, ...)** | sampling | sampling | no | no |
| **resistors, fixed, thick and thin film, chip** | sampling | 100 % | no | no |
| **switches, electromechanical** | 100 % | 100 % | 100 % | no |
| **switches, thermostatic** | 100 % | 100 % | 100 % | no |
| **thermistors** | 100 % | 100 % | no | no |
| **transformers** | sampling | 100 % | no | no |
| **transistors** | 100 % | sampling | 100 % | no |
| **transistors, microwave** | 100 % | sampling | 100 % | no |
| **wires and cables, low frequency** | sampling  (6.1.1n) | no | no | no |
| **cables, coaxial, radio frequency** | sampling  (6.1.1n) | no | no | no |
| **hybrids** | 100 % | 100 %  (6.1.1l) | 100 % | no |
| **surface acoustic waves** | 100 % | 100 % | 100 % | no |
| **charge coupled devices** | 100 % | 100 %  (6.1.1l) | 100 % | no |
| **opto discrete devices**  **(photodiodes, LED, phototransistors, optocouplers, …)** | 100 % | 100 % | 100 % | no |
| **HV Cable assembly** | 100% | 100% | no | no |
| **Cable assembly** | 100% | 100%  (6.1.1p) | no | no |

Seal test shall be performed on components made with a hermetic cavity package and as required in the applicable procurement specification.

For ceramic chip or moulded capacitors, electrical measurement shall be done after 4 hours of stabilisation at 125 °C for Type II ceramic.

Multi-chips (staked) capacitors shall be submitted to 100% visual inspection and electrical testing.

For all type of solid tantalum capacitors, the following specific tests shall be performed before the parametrical measurement:

Apply 9 discharges and 8 charges with a cycle time of 2 seconds and under nominal voltage and monitor the current during both charge and discharge tests to detect short circuit,

Perform a burn-in test for a duration or 96 hours at rated voltage at 85 °C

For all type of non-solid tantalum capacitors, the following specific test shall be performed before the parametrical measurement:

Perform a burn-in test for a duration or 96 hours at rated voltage at 85 °C.

For film capacitors using the polycarbonate technology, a DPA test shall be performed on three pieces, including:

external visual inspection,

sealing test after insulate sleeve removal,

microsection on two pieces, and

decaping on third part.

For programmed parts, the total duration, including storage and mission, shall not exceed data retention duration given by the manufacturer.

For VLSI, hybrids and CCD, when electrical test is not practicable because of test program or product complexity, the validation may be transferred to use step such as functional tests or programming stages.

1. For example, VLSI can be ASIC, FPGA, MMIC, DSP, microprocessors, microcontrollers.

For electromagnetic relays of latching and non-latching type, 10 switching shall be run before electrical measurements.

For low frequency and radio-frequency wires and cables, at least 0,5 m shall be inspected and insulating material shall be removed on 0,2 m.

Electrical test shall be optional for cavity hermetically sealed qualified parts when the qualification level is in line with the quality level defined by the applicable Tables 7-1, Table 7-2 or Table 7-3 of ECSS-Q-ST-60.

Electrical test shall be limited to insulation resistance test.

When relifed, commercial components shall be tested as defined in Table 6‑1 providing in addition, the following:

the availability of endurance test results on the flight lot,

the availability of humidity test results on the flight lot as per ECSS-Q-ST-60-13, in case of non-hermetic package sensitive to humidity,

the availability of a report of DPA performed on 3 pieces for each lot of commercial components in the frame of the relifing procedure.

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1 <<deleted and moved to 6.1.1m

<<deleted, modified and moved to 6.1.1n>>

<<deleted, modified and moved to 6.1.1o>>

### Electrical testing

A subset of DC parameters as given in the Table of room temperature electrical measurements of the relevant procurement specification, ESCC or equivalent, shall be selected, submitted to customer’s approval on request and then measured.

1. 1 It is important to pay attention to the test and set up procedures which can have changed since the initial date code.
2. 2 Additional burn-in and drift calculation to be performed are only those specified in Table 6‑1 of this standard.

### External visual inspection

In case of doubt or anomaly regarding any surface contamination, one part shall be sampled in order to make a solderability test according to the applicable test method.

The solderability test results shall be recorded in the relifing report.

The part tested for solderability shall be considered destroyed.

External Visual Inspection shall be done in accordance with applicable procurement specifications.

### Seal test

The sealing tests shall be recorded as "pass" where the results meet the requirements of the original procurement specification.

1. Sealing tests include fine leaks or gross leaks or both, depending on the applicable specification.

The measurement values of leaks on non-conforming components shall be recorded in the relifing report.

## Nonconformance

ECSS-Q-ST-10-09 shall apply for the handling and processing of nonconformances.

1. The processing of nonconformances is identical for both relifing and normal procurement procedures.

Any components not satisfying at least one of the requirements included in this standard shall be considered as not conform.

When performing the sampling test , as per Table 6‑1, any batch of components failing the sampling rule defined in requirement 6.1.1c shall be considered as not conform.

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In the case specified in 6.2c, the test shall be repeated on a 100% basis on the whole lot and the causes of the nonconformance investigated and recorded in the relifing report.

In case of 100% test, as per Table 6‑1, any batch of components shall be declared as not conform when failing the following requirement:

lot size < 100 parts : 0 defect allowed

lot size > 100 parts : 1 defect allowed

## Relifing datecode

The relifing date code shall correspond to the week code of the last test performed on the lot.

This date code shall be assigned independent of the report conclusions.

The relifing date code shall not be marked on the component and no other additional marking added.

## Relifing report

When relifing a component, a relifing report shall be established and sent, on request, to the customer for information.

1. Guidelines of an Relifing report are given in Annex C.

## Certificate of Conformity

Once a batch is accepted, supported by a relifing report giving an “acceptable” decision or as a result of NCR processing, the original Certificate of Conformity shall be annotated with the relifing date code.

The Certificate of Conformity shall be delivered with the components.

Discarded batches shall be processed internally by the relevant reject system of the supplier.

The relifing NCR, if any, signed and dated by the supplier, shall be delivered with the components.

Table 6‑1: <<deleted, modified and moved as new Table 6‑1>>



# Control parameters for class 3 programmes

## Test requirements

### Requirements per EEE parts family

For relifing, the following tests, as specified in Table 7‑1 shall be performed:

External Visual Inspection

Electrical measurements

Specific test

1. The relifing procedure can be applied on a sub-lot containing only the quantity of components immediately needed for production. In this case, the relifing date-code is applicable only to parts actually tested. The time limits specified in Table 5‑1 remain applicable for the residual sub-lot.

When sampling is specified in Table 7‑1, it shall be performed in accordance with AQL 0,65 % level II according to ANSI ASQ Z1.4.

Only the components which are listed in Table 7‑1 are concerned by Class 3 programmes relifing requirements. No relifing is required for components which are not listed in the Table 7‑1

The specifications and methods to be used during relifing shall be those that were in effect for the initial procurement or, if demonstrated that they are not applicable, the most recent updated issues.

Table 7‑1: Control parameters and detailed application of categories

|  | External Visual Inspection | ELECTRICAL | SPECIFIC  TESTS |
| --- | --- | --- | --- |
| **capacitors, glass (CYR, …)** | 100 % | 100 % | no |
| **capacitors, chip, solid tantalum**  **(TAJ, T495, CWR11, …)** | sampling | 100 % | yes  (see 0) |
| **capacitors, leaded, solid tantalum**  **(CSR, …)** | sampling | 100 % | yes  (see 0) |
| **capacitors, leaded,**  **non solid (tantalum,(CLR79, …)** | 100 % | 100 % | yes  (see 7.1.1f) |
| **through-hole components using glass beads** | 100% | no | no |
| **opto discrete devices**  **(photodiodes, LED, phototransistors, optocouplers, …)** | 100 % | 100 % | no |
| **Hybrids** | 100 % | 100 %  (see 7.1.1g) | no |
| **oscillators (hybrids)** | 100 % | 100 % | no |
| **commercial active components** | 100% | sampling  (see 7.1.1g) | no |

For all type of solid tantalum capacitors, the following specific tests shall be performed before the parametrical measurement:

Apply 9 discharges and 8 charges with a cycle time of 2 seconds and under nominal voltage and monitor the current during both charge and discharge tests to detect short circuit.

Perform a burn-in test for a duration of 96 hours, at rated voltage, at 85 °C.

For all type of non-solid tantalum capacitors, the following specific tests shall be performed before the parametrical measurement:

Perform a burn-in test for a duration of 96 hours, at rated voltage, at 85 °C.

For hybrids and commercial active parts, when electrical test is not practicable because of test program or product complexity, the validation may be transferred to use step such as functional test or programming stage.

When relifed, commercial components shall be tested as defined in Table 7‑1, providing in addition the following:

the availability of lifetest test results on the flight lot,

the availability of humidity test results on the flight lot as per ECSS-Q-ST-60-13, in the case of non-hermetic package sensitive to humidity,

a DPA shall be performed on 3 pieces for each lot of commercial components in the frame of the relifing procedure.

### Electrical testing

A subset of DC parameters, as given in the Table of room temperature electrical measurements of the relevant procurement specification, ESCC or equivalent, shall be selected, submitted to customer’s approval and then measured.

1. 1 It is important to pay attention to the test and set up procedures which can have changed since the initial date code.
2. 2 Additional burn-in to be performed are only those specified in Table 7‑1.

### External visual inspection

In case of doubt or anomaly regarding any surface contamination, one part shall be sampled in order to make a solderability test according to the applicable test method.

The solderability test results shall be recorded in the relifing report.

The part tested for solderability shall be considered destroyed.

In case of doubt or anomaly in the integrity of the glass sealing, parts shall be submitted to seal test according to the applicable test method.

## Nonconformance

ECSS-Q-ST-10-09 shall apply for the handling and processing of nonconformances.

1. The processing of nonconformances is identical for both relifing and normal procurement procedures.

Any components not satisfying at least one of the requirements included in this standard shall be considered as not conform.

When performing the sampling test, as per Table 7‑1, any batch of components failing the sampling rule defined in requirement 7.1.1b shall be considered as not conform.

In the case specified in 7.2c, the test shall be repeated on a 100 % basis on the whole lot and the causes of the nonconformance investigated and recorded in the relifing report.

In case of 100 % test, as per Table 7‑1, any batch of components shall be declared as not conform when failing the following “pass” conditions:

lot size < 100 parts: 0 defect allowed

lot size > 100 parts: 1 defect allowed

## Relifing datecode

The relifing date code shall correspond to the week code of the last test performed on the lot.

This date code shall be assigned independent of the report conclusions.

The relifing date code shall not be marked on the component and no other additional marking added.

## Relifing report

When relifing a component, a relifing report shall be established and sent, on request, to the customer for information.

1. Guidelines of an Relifing report are given in Annex C.

## Certificate of Conformity

Once a batch is accepted, supported by a relifing report giving an “acceptable” decision or as a result of NCR processing, the original Certificate of Conformity shall be annotated with the relifing date code.

The Certificate of Conformity shall be attached with the components during their delivery.

Discarded batches shall be processed internally by the relevant reject system of the supplier.

The relifing NCR, if any, signed and dated by the supplier, shall be delivered with the components.

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1. (informative)  
   Guidelines for a Relifing report
   1. Purpose of the Relifing report

The purpose of this document is to:

1. give the detailed references of the lot tested,
2. describe the relifing tests performed,
3. give the results obtained,
4. give the date of tests.
   1. Content of the Relifing report
5. The Relifing report gives the following generic information:
   1. part style
   2. detailed specification (with issue and variant)
   3. item identification by the supplier
   4. quantity stored
   5. original datecode
   6. date of storage
6. For each test, the Relifing report indicates:
   1. operator
   2. date of test
   3. quantity tested
   4. quantity rejected
   5. comments
7. The Relifing report includes a conclusion, either accepted or rejected.
8. The Relifing report indicates, after relifing, the new datecode.
9. Figure C-1 shows a proposed template of a Relifing report.

|  |  |  |  |
| --- | --- | --- | --- |
| Part Style: | | | |
| Detailed specification: | | Issue: | Var: |
| Item identification at User: | | | |
| Quantity Stored: | | Date code: | Date of Storage: |
| TESTS | RELIFING | | |
| 1. External visual |  | | |
| Operator |  | | |
| Date |  | | |
| Quantity tested |  | | |
| Quantity rejected |  | | |
| Comments |  | | |
| 2. Electrical tests |  | | |
| Operator |  | | |
| Date |  | | |
| Quantity tested |  | | |
| Quantity rejected |  | | |
| Comments |  | | |
| 3. Hermeticity |  | | |
| Operator |  | | |
| Date |  | | |
| Quantity tested |  | | |
| Quantity rejected |  | | |
| Comments |  | | |
| 4. DPA (if any) |  | | |
| Operator |  | | |
| Date |  | | |
| Quantity tested |  | | |
| Results |  | | |
| DPA Report number |  | | |
| 5. Other tests |  | | |
| Conclusion:  Accepted / Rejected |  | | |
| New date code |  | | |

: Example of a relifing traveller sheet

# Bibliography

|  |  |
| --- | --- |
| ECSS-S-ST-00 | ECSS system – Description, implementation and general requirement. |
| MIL-HDBK-263B, July 1994 | Electrostatic Discharge Control Handbook for protection of Electronic Parts, Assemblies and Equipment (excluding Electrically Initiated Explosive Devices) |